



US00D835804S

(12) **United States Design Patent** (10) **Patent No.:** **US D835,804 S**
Ito et al. (45) **Date of Patent:** **** Dec. 11, 2018**

(54) **SUBSTRATE FOR SPECTROSCOPIC ANALYSIS**

3/5027; G01N 1/405; G01N 35/00009;
G01N 1/312; B01J 19/0046; B01J
2219/00596

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See application file for complete search history.

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(**) Term: **15 Years**

(21) Appl. No.: **35/502,713**

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(80) **Hague Agreement Data**

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Primary Examiner — Richard E Chilcot

(57) **CLAIM**

The ornamental design for a substrate for spectroscopic analysis, as shown and described.

DESCRIPTION

(30) **Foreign Application Priority Data**

Apr. 27, 2016 (JP) 2016-009319

(51) **LOC (11) Cl.** **24-02**

(52) **U.S. Cl.**
USPC **D24/225**
CPC **G01N 1/405** (2013.01)

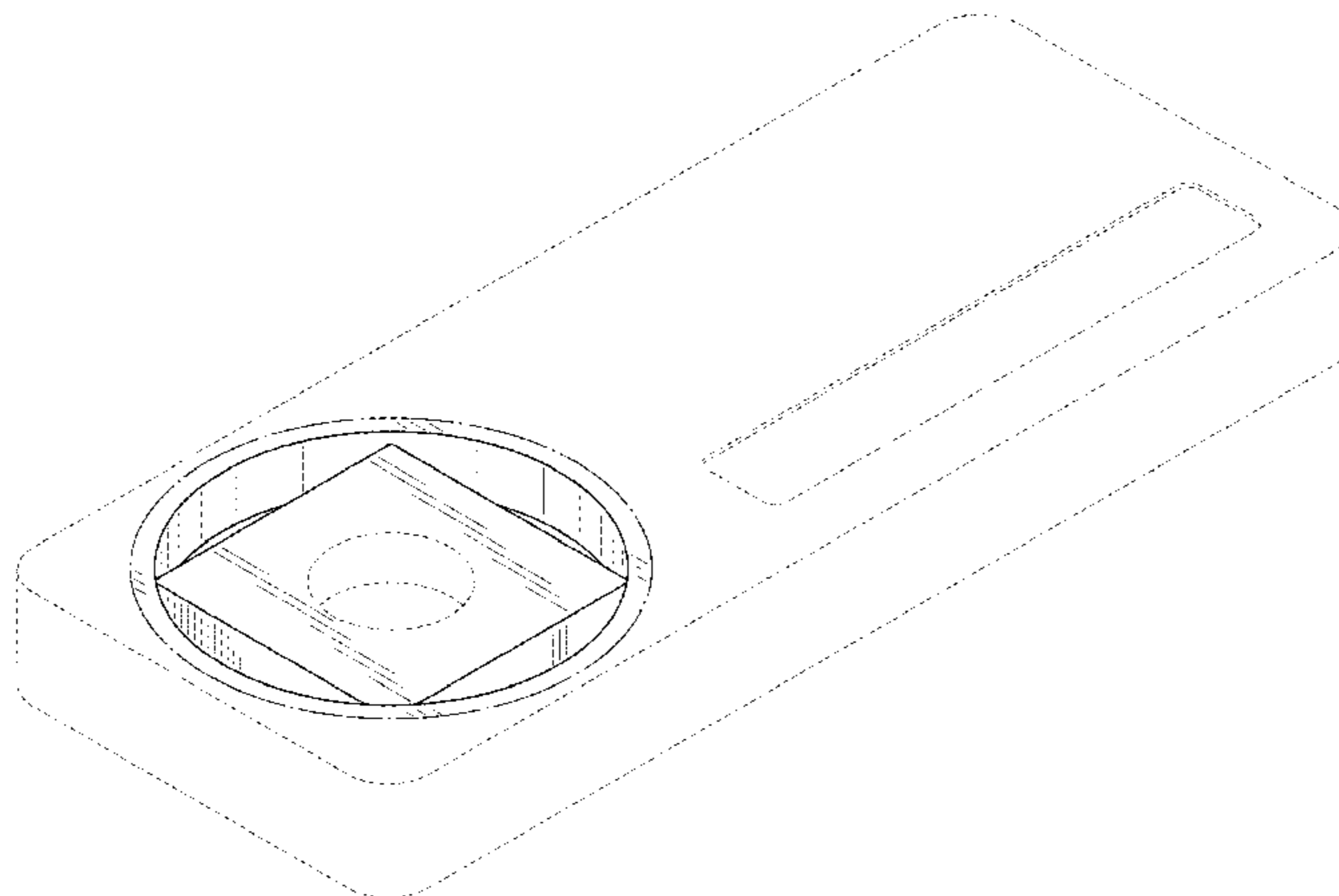
(58) **Field of Classification Search**

USPC D24/216, 222–226, 231, 232, 169;
D10/80, 81; 422/68.1, 69, 502–507, 430,
422/560–566, 547; 435/283.1,
435/288.1–228.4, 289.1
CPC B01L 2300/0816; B01L 2400/0406; B01L
9/54; B01L 9/06; B01L 9/52; B01L
9/543; B01L 9/00; B01L 3/5085; B01L

- 1. Substrate for spectroscopic analysis
- 1.1 : Perspective
- 1.2 : Front
- 1.3 : Back
- 1.4 : Top
- 1.5 : Bottom
- 1.6 : Left
- 1.7 : Right
- 1.8 : Cross-sectional
- 1.9 : Cross-sectional
- 1.10 : Perspective view without the cover part

The broken line showing the substrate for spectroscopic analysis is for the purpose of illustrating environmental structure and forms no part of the claimed design.

(Continued)



The dot-dash broken lines define the bounds of the claimed design and form no part thereof.

1 Claim, 10 Drawing Sheets

(56)

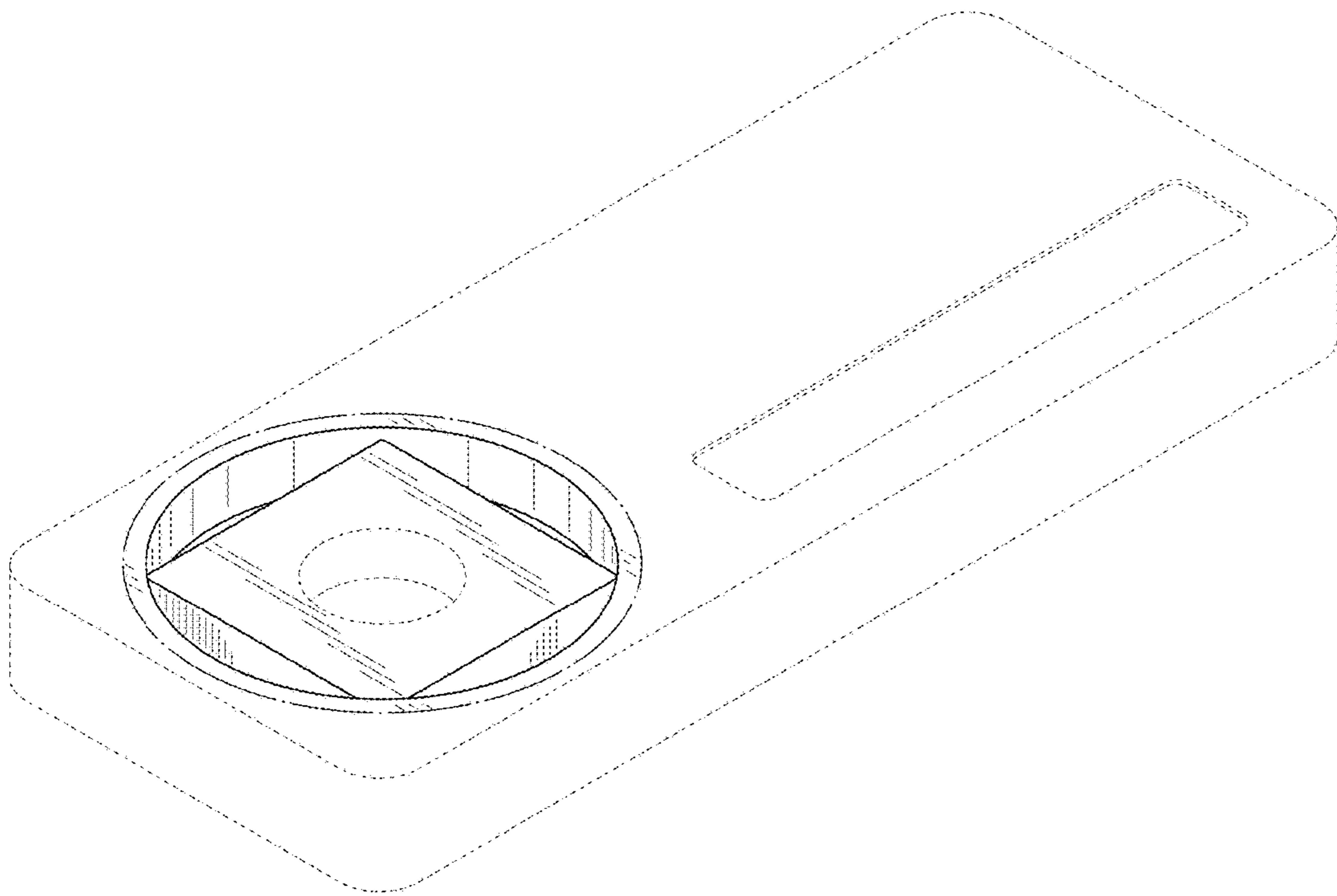
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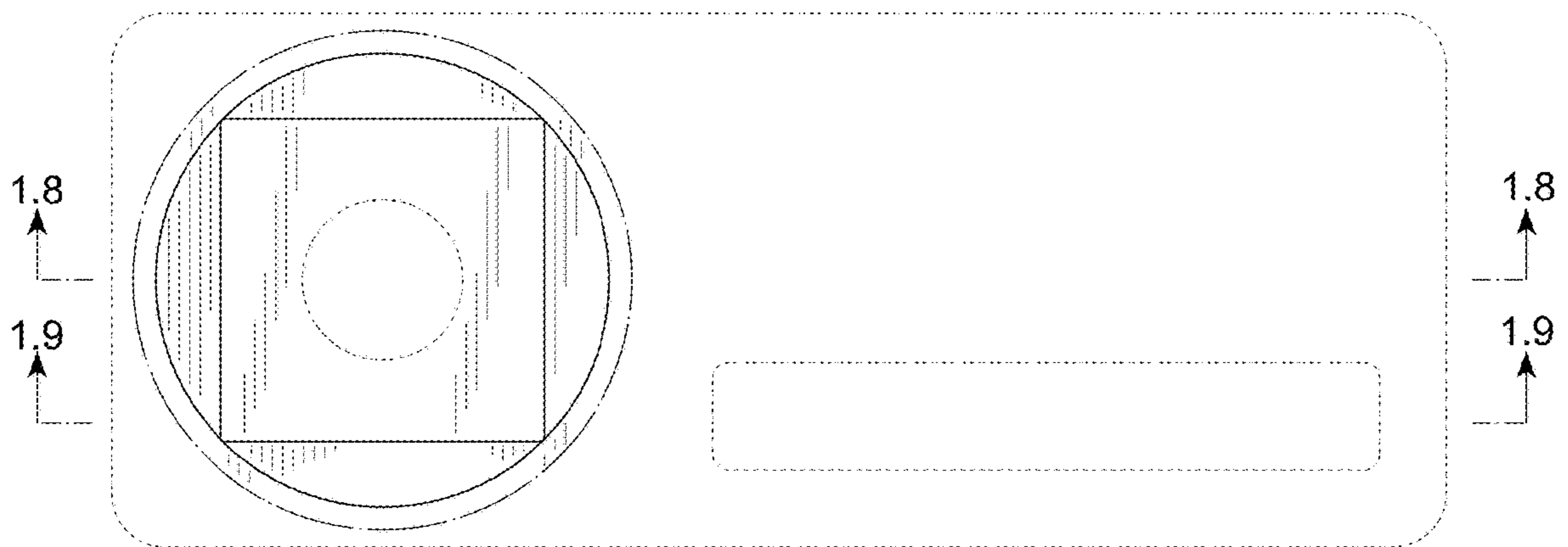
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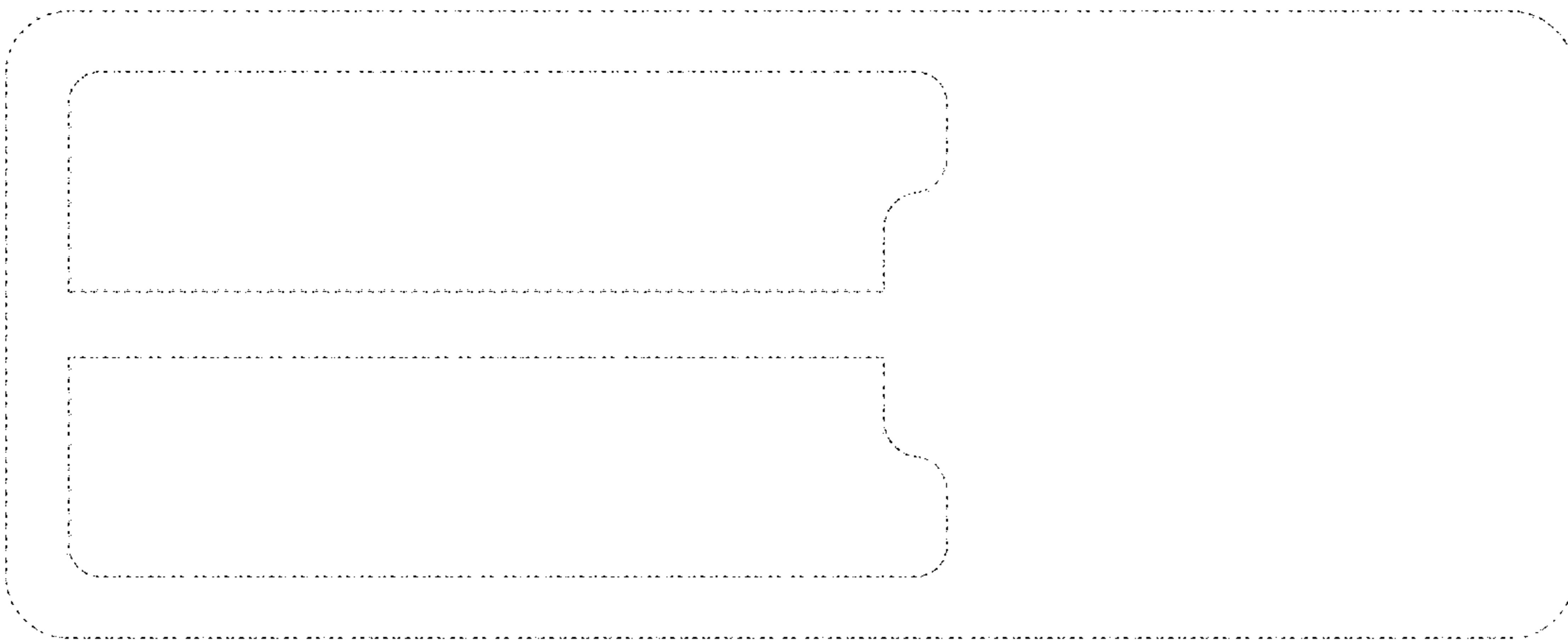
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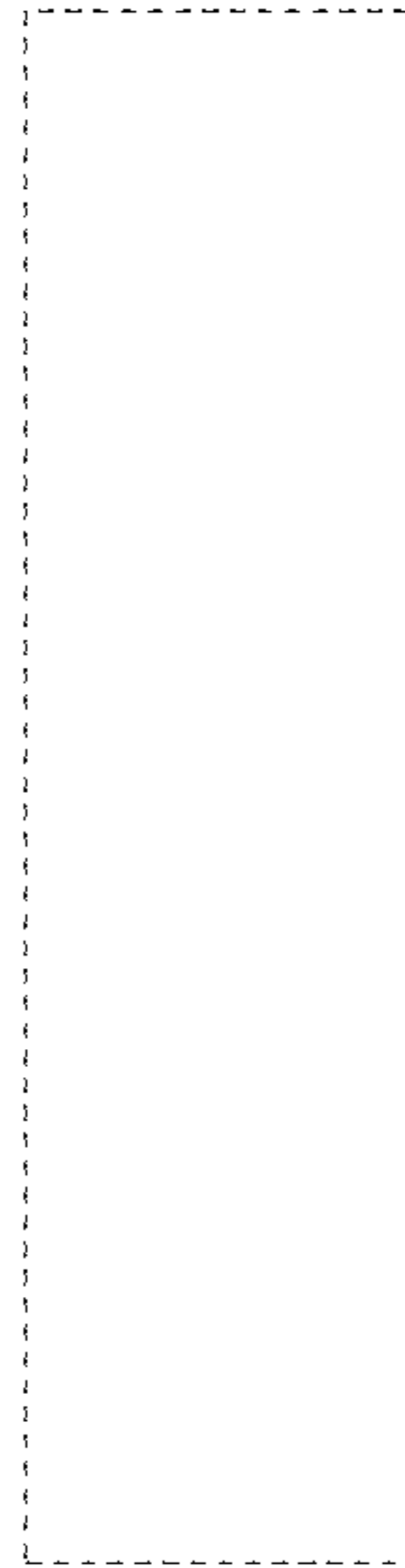
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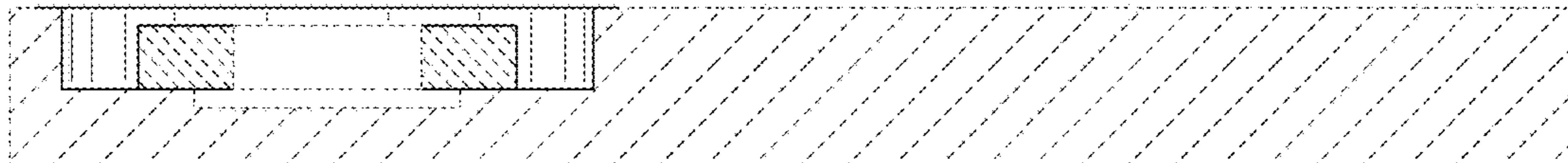
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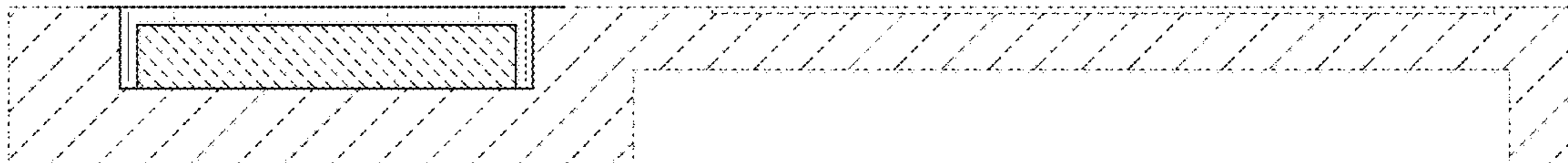
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1.8



1.9



1.10

